

(74H50J,N)



One side of this dual device consists of two 2-input AND gates ORed together and driving an output inverter. The other side consists of two 2-input gates ORed together, driving an output inverter, and the ORing nodes are available for expansion. Up to four AND gates can be ORed together using the MC3030/3130 expander. Care should be taken to minimize the amount of capacitance on the expander terminals in order to maintain switching speeds.

MC3100/MC3000 series



Output Loading Factor = 10 Total Power Dissipation = 62.5 mW typ/pkg Propagation Delay Time = 6.0 ns typ



SWITCHING TIME TEST CIRCUIT AND WAVEFORMS

shall be CT-070-50 or equivalent. See General Information section for packaging.

ELECTRICAL CHARACTERISTICS

Test procedures are shown for only one gate. The other gate is tested in the same manner. Lurther, test procedures are shown for only one input of the gate under test. To complete testing, sequence through re-maining inputs.



1		5	¢	9								L						TEST (CURREN	11/101	TEST CURRENT/VOLTAGE VALUES	JES						
1 -	Ĺ	Ц	5							0	@ Test			шA								Volts						
1										Ter	Temperature	e lot		и но	a1	- F	lexe	Vn	V _{IH}	۲,	V,	V _{RH}	Vmax	V _{cc}	Vcct	VccH	V _{iHX}	
											(-55°C	C 20	0 -2.0	- 0	•	0.3	0.55	1.1	2.0	0.4	2.4	4.0		5.0	4.5	5.5		
									×	MC3120	\ +25°C	C 20	-	-2.0 1.0	-10	0.3	0.71	1.1	1.8	0.4	2.4	4.0	7.0	5.0	4.5	5.5	2.5	
											(+125°C	C 20	-2.0	- 0		0.3	0.92	0.8	1.8	0.4	2.4	4.0		5.0	4.5	5.5		
											0°C)	C 20	-	-2.0 -	•	0.3	0.65	1.1	2.0	0.4	2.5	4.0	-	5.0	4.75	5.25		
									-	MC3020		C 20	-	-2.0 1.0	-10	0.3	0.71	1.1	1.8	0.4	2.5	4.0	7.0	5.0	4.75	5.25	2.5	
	-										(+75°C	C 20		-2.0 -		0.3	-	0.82 0.9 1.8	1.8	0.4	2.5	4.0	;	5.0	4.75	5.25		
1		MC3121	MC3120 Test Limits	imits			W	MC3020 Test Limits	Test Lim	its						TEST	CURREN	T / V0	TAGE	APPLIE	SUID DI C	FEST CURRENT / VOI TAGE APPI IEN TO PINS LISTEN BEI OW	·MC					
E * 1	-55°C	+25°C	5°C	+125°C	5°C	0°C	-	+25°C	-	+75°C	_	1	$\left \right $	ł	-													
1:5	Min Max	-	Max	Min	Min Max	Min Max		Min N	×	Min Max	ix Unit	_	loi loh	H	-		¹ EXE	ч <mark>к</mark>	H ×	× <	V,R	V _{RH}	Vmax	>	V cc1	VccH	VIHX	Gnd
1 .	-2.0	•	-2.0	1	-2.0		-2.0	1	-2.0	2.	-2.0 mAdc	-	-	-	•	-		,	1	-		13				14		7, 9, 10*
1	50		50		50		50		50	- 50	0 µAdc		'	-	1	•		'			1					14		7, 9, 10, 13*
11.	•	5.5			1.	1.1		5.5		•	Vdc	-	· 	-	·		•		1							14		7, 9, 10, 13*
1.	1		-1.5		1				-1.5	-	Vdc	-	-	-	-		•	,	•						14			7, 9, 10*
1.1	0.4	н. н. 1	0.4	• 5	0.4		0.4		0.4	- 0.4	4 Vdc 4 Vdc	8 8		• •			11, 12		1		1.1	13		1.13	14 14	• •		7, 9, 10 * 1,7,9,10,13
1.75	2.4 -	2.4	1	2.4		2.5		2.5	- 3	2.5 -	Vdc	-	80	•			•	1				13	1	1	14		•	1, 7, 10 *
12	-40 -100	-40	-100	-40	-100	-40	-100	-40 -	-100	-40 -100	00 Vdc	-	1.	•	•	•	•		•							14	ŕ,	1, 7, 8, 9, 10, 13 *
	- 1.10						1.00			•	Vdc	8	-			۰.	11, 12				-	-	•		14	-	1	1, 9, 10, 13*
1 00	0.80 -	0.65		0.45		0.70	-	0.65	- 0.	0.55 -	Vdc	'		•	1	11	-						•		14		,	1, 9, 10, 12,13*
						ŀ							-					Í										

Pin Under Test

Symbol

Characteristic

-

--00 8 8

BVin

Breakdown Voltage

Leakage Current

4D

Clamp Voltage

VoL

Output Output Voltage

NOH

sc

Short-Circuit Current

-

Ŀ IR I

Forward Current

Since this is an inverting gate, power drain is minimized by grounding the inputs to gates not under test.

1,2,3,4,5,7, 9,10,13

,

i.

14 14

. .

1, 2, 3, 4, 5, 9, 10, 13 ī

.

.

,

1

,

.

.

24 12.8

24

24 12.8

24 12.8

ï

12.8

i

1

,

12.8

.

12.8 24

14 14

I PDH I PDL

Dower Supply Drain

14 . , .

. . 14

. . i. .

. ,

. 4 . .

11 . . ,

> i. <u>,</u>

0.80 . . ï

11 11

VBE max VBE min

Base-Emitter Voltage

• . ,

÷

.

. . . Pulse out ∞ 80

, , ,

mAdc mAdc mAdc

,

1 .

24 .

> . .

i.

. ,

.

, .

24 24

i. .

14

Imax

Power Requirement (Total Device) Maximum Power Supply Current

1,2,3,4,5,7, 9,10,13

7, 9, 10 * 7, 9, 10 *

13 13

,

14 14

.

. .

, .

.

• ,

ī .

, .

,

1

- Inse

. 1

, ,

Ξ

.

• .

Ξ 11

.

ı, .

r ,

1, 8

t pd-

Switching Parameters Turn-On Delay

.

1, 8

tpd+

Turn-Off Delay

,

.

-

ns us

11

ï ,

,

ı,

.

i.